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Discussion Session: Defect Engineering & Pad Detectors (MCZ, EPI, FZ)

Monday, 2 June 2008 16:00 (30 minutes)

Presenters: FRETWURST, Eckhart (Unversity of Hamburg, Germany); KRAMBERGER, Gregor (Jozef Stefan

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Session Classification: Defect Engineering & Pad Detector Characterization I